Se	arcn	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/765,251	SHEN ET AL.	
Examiner	Art Unit	
Yonel Beaulieu	3661	

	SEAR	CHED	
Class	Subclass	Date	Examiner
701	1	10/8/2005	YB
	19		
	20		
104	165	10/9/2005	YB
246	2R	10/9/2005	YB
	34R		
	61		
280	124.108	10/9/2005	YB
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH (INCLUDING SEAR	NOTES CH STRATEGY)
	DATE	EXMR
WEST/Inv./Fwd-Bkwd	10/9/2005	YB
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